

Measurement Report for AIHS–MU, , , CW, Channel 0 (13.000 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
AIHS–MU, UIM Pressure Implant Inc	50.0 x 10.0 x 30.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid			CW, 0–	13.000, 0	15.0	0.781	52.8

Hardware Setup

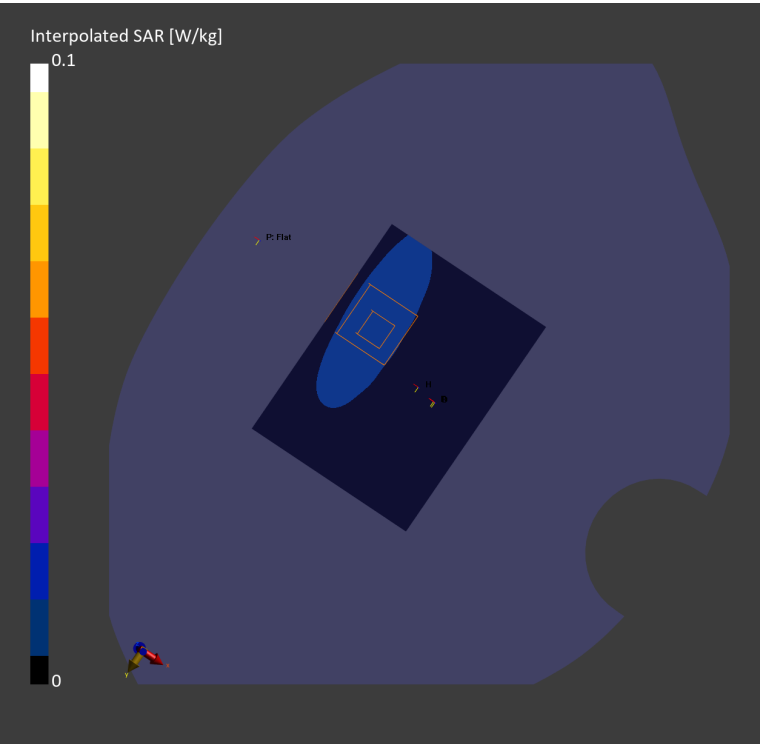
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin–SAM V8.0 (30deg probe tilt) – 2186	HBBL4–250V3 Charge:xxxx, 2025–08–27	EX3DV4 – SN7871, 2025–06–23	DAE4ip Sn1907, 2025–05–05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025–08–27, 12:05	2025–08–27, 12:37
psSAR1g [W/Kg]	0.011	0.011
psSAR10g [W/Kg]	0.009	0.007
Power Drift [dB]	–0.16	0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.2
Dist 3dB Peak [mm]		14.4



Measurement Report for AIHS–MU, FRONT, Custom Band, CW, Channel 13600 (13.600 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
AIHS–MU, UIM Pressure Implant Inc	400.0 x 400.0 x 40.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	FRONT, 0.00	Custom Band	CW, 0--	13.600, 13600	15.0	0.781	52.8

Hardware Setup

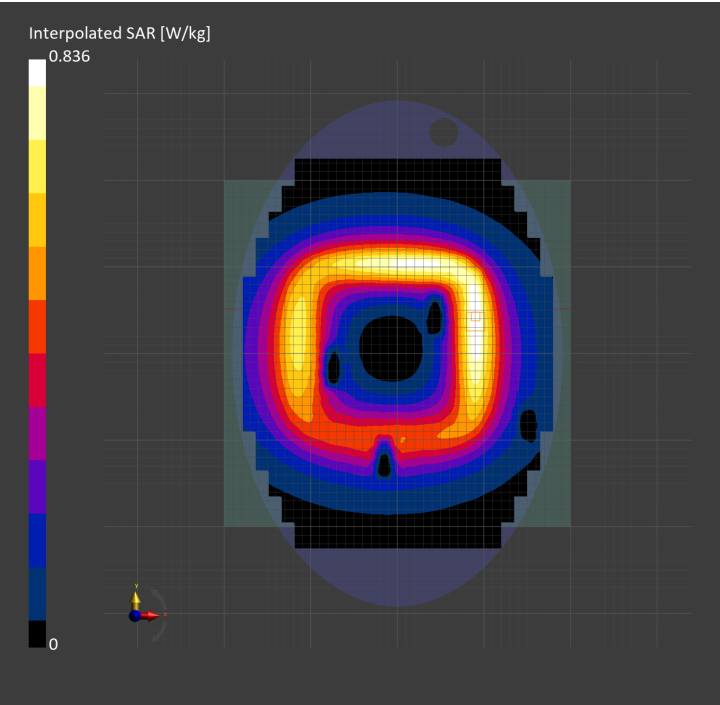
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – 2237	HBBL4–250V3 Charge:xxxx, 2025–08–27	EX3DV4 – SN7871, 2025–06–23	DAE4ip Sn1907, 2025–05–05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	450.0 x 450.0	x x
Grid Steps [mm]	15.0 x 15.0	x x
Sensor Surface [mm]	3.0	
Graded Grid	N/A	
Grading Ratio	N/A	
MAIA	N/A	
Surface Detection	VMS + 6p	
Scan Method	Measured	

Measurement Results

	Area Scan	Zoom Scan
Date	2025–08–27, 19:29	
psSAR1g [W/Kg]	0.786	
psSAR10g [W/Kg]	0.652	
Power Drift [dB]	–0.01	
Power Scaling	Disabled	
Scaling Factor [dB]		
TSL Correction	No correction	
M2/M1 [%]		
Dist 3dB Peak [mm]		



Measurement Report for AIHS–MU, BACK, Custom Band, CW, Channel 13600 (13.600 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
AIHS–MU, UIM Pressure Implant Inc	400.0 x 400.0 x 40.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	BACK, 0.00	Custom Band	CW, 0--	13.600, 13600	15.0	0.781	52.8

Hardware Setup

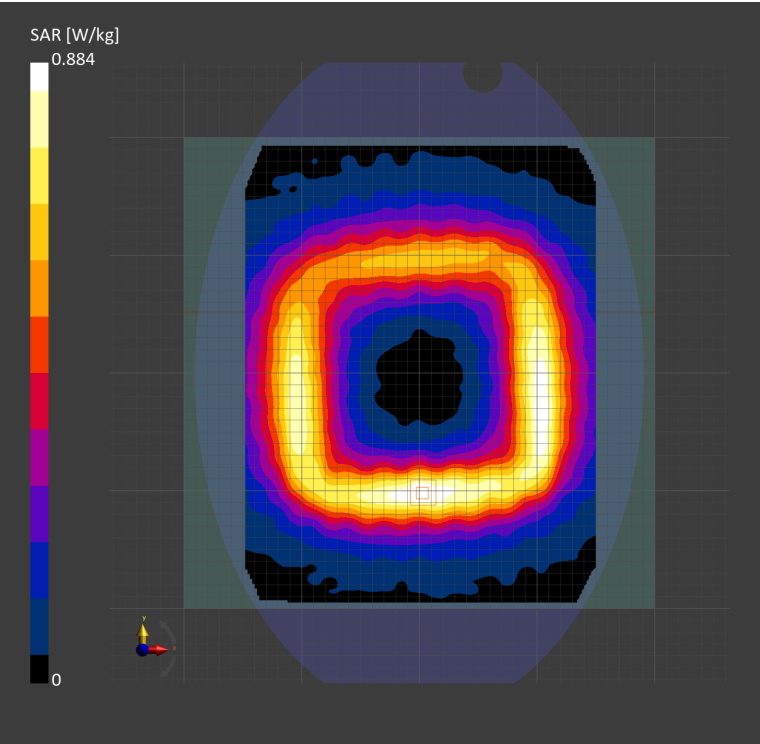
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – 2237	HBBL4–250V3 Charge:xxxx, 2025–08–27	EX3DV4 – SN7871, 2025–06–23	DAE4ip Sn1907, 2025–05–05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	300.0 x 390.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025–08–27, 13:13	2025–08–27, 17:30
psSAR1g [W/Kg]	0.912	0.866
psSAR10g [W/Kg]	0.758	0.608
Power Drift [dB]	0.01	–0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.0
Dist 3dB Peak [mm]		16.8



Measurement Report for AIHS–MU, EDGE LEFT, Custom Band, CW, Channel 13600 (13.600 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
AIHS–MU, UIM Pressure Implant Inc	400.0 x 400.0 x 40.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE LEFT, 0.00	Custom Band	CW, 0--	13.600, 13600	15.0	0.781	52.8

Hardware Setup

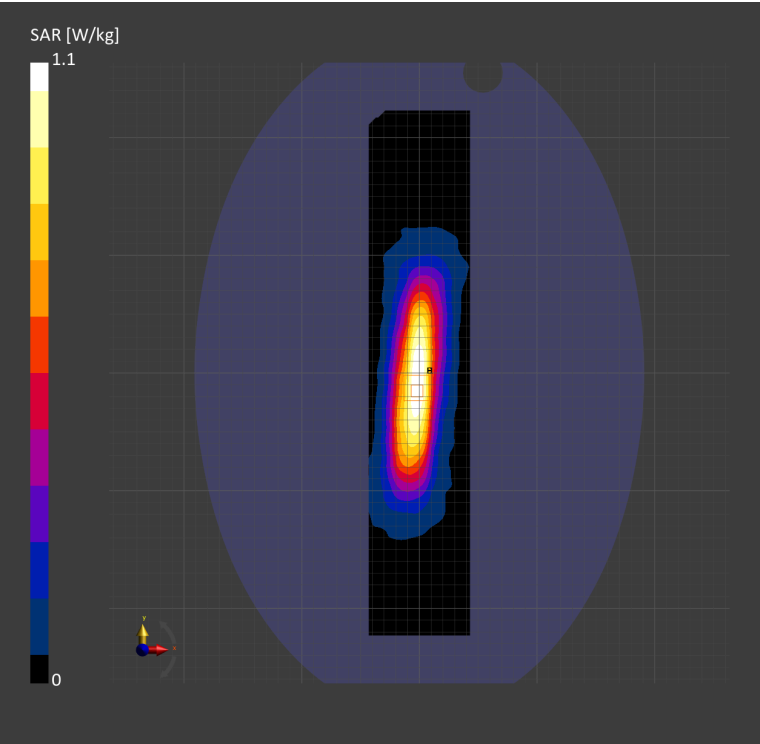
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – 2237	HBBL4–250V3 Charge:xxxx, 2025–08–27	EX3DV4 – SN7871, 2025–06–23	DAE4ip Sn1907, 2025–05–05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 450.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025–08–27, 18:18	2025–08–27, 18:34
psSAR1g [W/Kg]	1.12	1.10
psSAR10g [W/Kg]	0.892	0.675
Power Drift [dB]	–0.03	–0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.6
Dist 3dB Peak [mm]		6.0



Measurement Report for AIHS–MU, EDGE RIGHT, Custom Band, CW, Channel 13600 (13.600 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
AIHS–MU, UIM Pressure Implant Inc	400.0 x 400.0 x 40.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE RIGHT, 0.00	Custom Band	CW, 0--	13.600, 13600	15.0	0.781	52.8

Hardware Setup

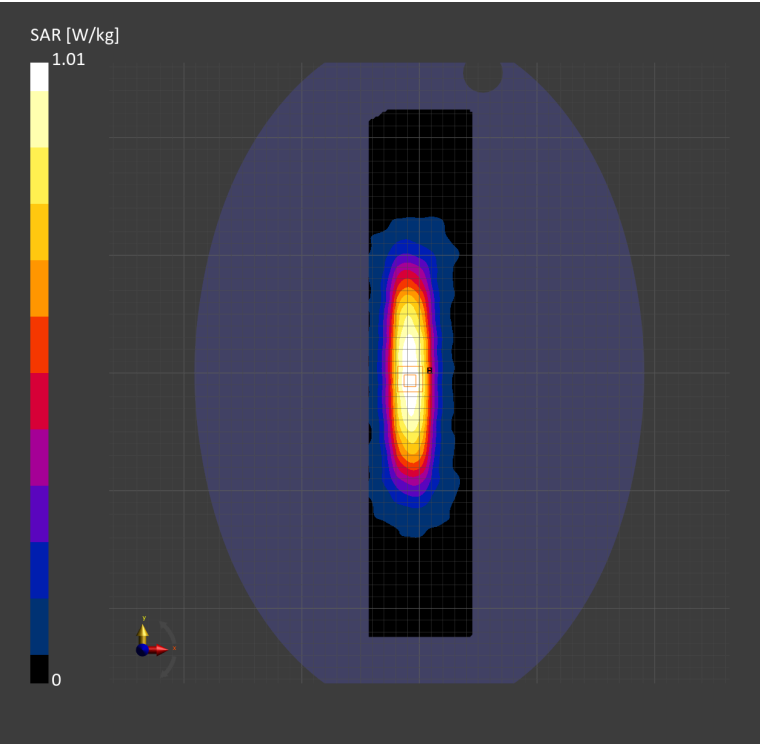
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – 2237	HBBL4–250V3 Charge:xxxx, 2025–08–27	EX3DV4 – SN7871, 2025–06–23	DAE4ip Sn1907, 2025–05–05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 450.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025–08–27, 18:42	2025–08–27, 18:57
psSAR1g [W/Kg]	1.05	1.06
psSAR10g [W/Kg]	0.857	0.664
Power Drift [dB]	0.01	–0.07
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.8
Dist 3dB Peak [mm]		13.2



Measurement Report for AIHS–MU, EDGE TOP, Custom Band, CW, Channel 13600 (13.600 MHz)

Device Under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
AIHS–MU, UIM Pressure Implant Inc	400.0 x 400.0 x 40.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	EDGE TOP, 0.00	Custom Band	CW, 0--	13.600, 13600	15.0	0.781	52.8

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
ELI V8.0 (20deg probe tilt) – 2237	HBBL4–250V3 Charge:xxxx, 2025–08–27	EX3DV4 – SN7871, 2025–06–23	DAE4ip Sn1907, 2025–05–05

Scans Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	90.0 x 450.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025–08–27, 17:52	2025–08–27, 18:08
psSAR1g [W/Kg]	1.02	0.978
psSAR10g [W/Kg]	0.807	0.615
Power Drift [dB]	0.01	–0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.9
Dist 3dB Peak [mm]		6.5

